

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/088,705	MIURA ET AL.	
Examiner	Art Unit	
Daquan Zhao	2621	

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Class	Subclass	Date	Examiner
386	47	10/8/2007	DZ

INI	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPAT; USPGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB (see search note attached)	10/8/2007	dz	
			